

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/768,166	WU ET AL.	
Examiner	Art Unit	
Kin-Chan Chen	1765	

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Keyworde search USPAT, USPG-Pub. Epo, JPO, Derwent IBM-TDB, inventor searce	10/3/2005	ксс		